# 15th Pacific Northwest Test Workshop

aka: BAST 2006

Bodega Bay, California, Feb 28 – Mar 3, 2006

**CALL FOR PARTICIPATION**

<table>
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<th>Committee:</th>
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<tr>
<td><strong>General Chair Emeritus:</strong> Edward J. McCluskey, Stanford CRC</td>
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<td><strong>General Chair:</strong> Siyad Ma, IDT</td>
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<td><strong>Program Chair:</strong> Samy Makar, Azul Systems</td>
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<td><strong>Registration Chair:</strong> Erik Volkerink, Agilent &amp; Stanford CRC</td>
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<td><strong>Registration Co-chair:</strong> Intaik Park, Stanford CRC</td>
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<td><strong>Industrial Donors:</strong> Garry Gillette, Credence</td>
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<td><strong>Finance Chair:</strong> Kyoung Youn (Ken) Cho, Stanford CRC</td>
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<td><strong>Entertainment Chair:</strong> Davia Lu, Intel</td>
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<td><strong>Steering Committee:</strong> Edward J. McCluskey, Stanford CRC; Subhasish Mitra, Intel &amp; Stanford CRC; Siyad Ma, IDT; Mike Purtell, National Semiconductor; Samy Makar, Azul Systems</td>
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<td><strong>Program Committee:</strong> Ravi Apte - Syntest; Phil Burlison, Inovys; R Chandramouli, Virage Logic; Jayabrata Dastidar, Altera; Scott Davidson, SUN Microsystem; Bill Eklow, Cisco Systems; Rohit Kapur, Synopsys; Kee Sup Kim, Intel; Mike Li, Wavecrest; Samiha Mourad, SCU; Bruce Parnas, Advantest; Bill Price, Philips; Mike Purtell, National Semiconductor; Burnell West, Credence</td>
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The 15th annual BAST workshop, co-sponsored by the Stanford University Center for Reliable Computing (CRC) and the IEEE Computer Society Test Technology Technical Council (TTTC), will be held February 28 – March 3, 2006, in Bodega Bay, California. BAST is an informal workshop whose objective is to bring together engineers from the Pacific Northwest to discuss current work on testing electronic circuits. Attendance at BAST is restricted to fewer than 50 persons in order to facilitate better sharing of ideas.

BAST workshop is **unique in that all attendees are on the program**; everyone attending is expected to stay at the workshop for its duration, and to participate. Interaction is encouraged during every presentation, and during breaks and social events. Programs and reports from previous BAST workshops are available from the web site listed at the bottom of this page.

Interested persons are invited to submit a proposal containing a brief abstract of what they would like to discuss. Possible suggestions include:

- SOC and SIP Test Methodology
- Low-cost ATE
- Defect Behavior and Detection
- Yield Analysis
- Online Test and Robust Designs
- Diagnosis
- System Test
- Reliability Screening
- Quality Level Prediction
- Test Cost
- Test Compression
- Validation and Verification
- Mixed Signal Testing
- Testing High Speed I/Os
- BIST
- Debug
- At-Speed Testing
- Failure Mode Diagnosis
- Memory Test and Repair
- DFM

This is not an exclusive list; all interesting abstracts related to test are invited for submission (see reverse side for application information). If you are interested in attending, please email a softcopy of your proposal immediately to:

Erik Volkerink  
E-mail: volkerin@crc.stanford.edu  
353 Serra Mall, Gates-2A, Room 234  
Voice: 650-725-0487  
Stanford, CA 94305-9020  
FAX: 650-725-7411

Applications to attend the workshop will be considered on a first come first serve basis. Your proposal submission will reserve you a place and is not considered a commitment. **Invitations will be sent out promptly upon receipt of your proposal.** There is no on-site registration.

BAST web site: [http://crc.stanford.edu/BAST/BAST.html](http://crc.stanford.edu/BAST/BAST.html)

(See Reverse Side)
Proposal for Participation, Please turn in immediately.

Name: ________________________________________________
Address: ________________________________________________
_____________________________________________________
Tel.: (                ) ______________ Fax: (                ) ______________
E-Mail: ________________________________________________
Company or University: _________________________________
Referred by (Optional): _________________________________

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<th>ATTENDEE INFORMATION</th>
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<td>Test Interests/experience</td>
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Abstract of your discussion: (Please be brief)

(See Reverse Side)